

INFORMATION DISCLOSURE 1449

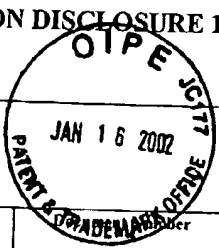
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Application No.: 09/889,961

Applicant: Cheng, et al.

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Group Art Unit: 1723



U.S. Patent Documents

* Examiner's Initial	Ref	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AF	*A1	4,902,456	02/90	Yen, et al.			
	A2	4,906,377	03/90	Yen, et al.			
	*A3	4,990,294	02/91	Yen, et al.			
	A4	5,032,274	07/91	Yen, et al.			
	A5	5,154,827	10/92	Ashelin, et al.			
	A6	5,158,680	10/92	Kawai, et al.			
	*A7	5,490,931	02/96	Chung, et al.			
	A8	5,695,702	12/97	Niermeyer			
	A9	5,762,789	06/98	de los Reyes, et al.			
AF	A10	5,855,783	01/99	Shucosky, et al			

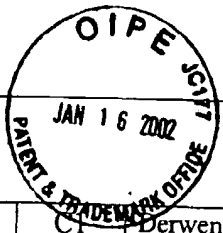
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FOREIGN PATENT DOCUMENTS

	Ref	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
AF	B1	DE 3444387	07/85	Germany				X
	B2	EP 0 175 432	03/86	EPO				
	B3	EP 0 217 482	04/87	EPO				
	B4	EP 0 299 459	01/89	EPO				
	B5	EP 0 340 732	11/89	EPO				
	B6	EP 0 343 247	11/89	EPO				
	B7	EP 0 559 149	09/93	EPO				
	B8	EP 0 803 281	10/97	EPO				
	B9	EP 0 855 212	07/98	EPO				
	*B10	FR 2 566 003	12/85	France				X
	B11	WO 00/44479	08/00	PCT				
	B12	WO 00/44480	08/00	PCT				
	*B13	WO 00/44482	08/00	PCT				
	B14	WO 00/44483	08/00	PCT				
	B15	WO 00/44484	08/00	PCT				
AF	B16	WO 00/44485	08/00	PCT				

Yen, et al. Portman

Date: 4/24/04



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OTHER DOCUMENTS

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Derwent Publication XP-002142276 Abstract of JP 04 354521

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Examiner:

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Date Considered:

4/26/04

Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant

* Indicates a cite that has been previously forwarded to the USPTO and is n t enclosed.